



ISSUE A

OP-26

m6T

MC5480 · MC7480 MC9380 · MC8380

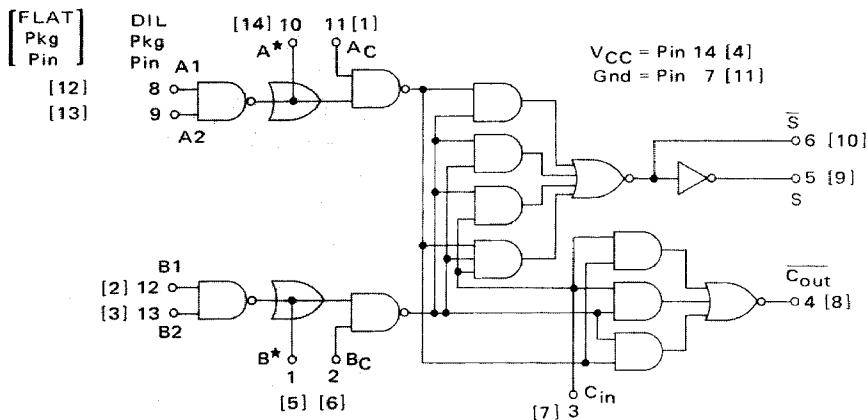
Add Suffix F for TO-86 ceramic package (Case 607).

Suffix L for TO-116 ceramic package (Case 632).

Suffix P for TO-116 plastic package (Case 646) MC7480, MC8380.

These devices are one-bit binary full adders with gated complementary inputs, complementary Sum and \bar{S} um outputs, and an inverted Carry output. The circuit uses DTL inputs and a high-speed, high-fan-out, TTL "totem pole" configuration for the Sum, \bar{S} um, and Carry outputs. The design of the high-speed carry circuitry reduces the need for external "look ahead carry" cascading in system designs. The use of low-level, low-power gates in a monolithic design provides significantly lower power dissipation than equivalent adders built from standard integrated circuits.

This full adder provides a basic building block for medium and high-speed, multiple-bit, parallel-add/serial-carry subsystems.



Input Loading Factor:

$$A_1, A_2, A_C, B_1, B_2, B_C = 1$$

$$A^*, B^* = 1.625$$

$$C_{in} = 5$$

Output Loading Factor:

$$\bar{C}_{out} = 5$$

$$S, \bar{S} = 10$$

$$A^*, B^* = 3$$

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TRUTH TABLE

C _{in}	B	A	\bar{C}_{out}	\bar{S}	S
0	0	0	1	1	0
0	0	1	1	0	1
0	1	0	1	0	1
0	1	1	0	1	0
1	0	0	1	0	1
1	0	1	0	1	0
1	1	0	0	1	0
1	1	1	0	0	1

$$1. A = \overline{A^* \cdot A_C}, B = \overline{B^* \cdot B_C}$$

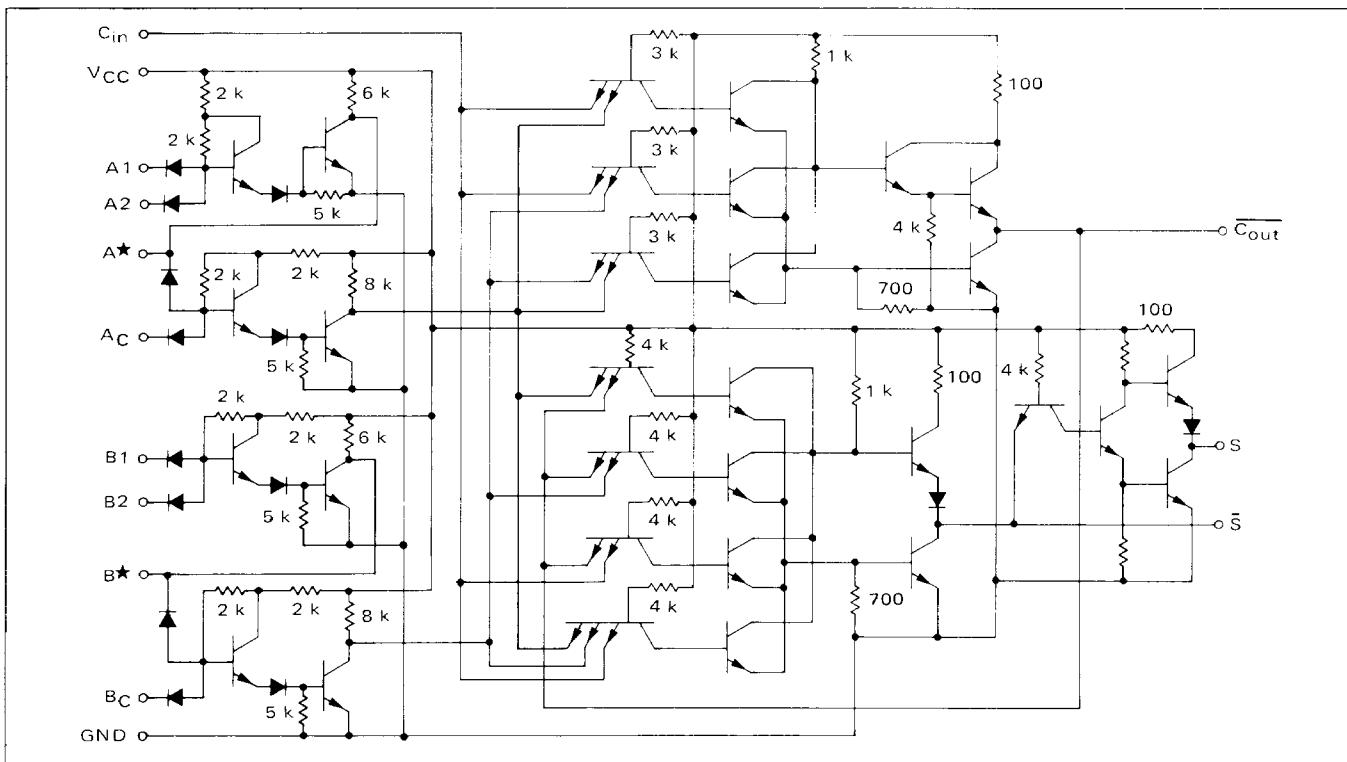
$$\text{where } A^* = \overline{A_1 \cdot A_2}$$

$$B^* = \overline{B_1 \cdot B_2}$$

2. When A^* (or B^*) is used as an input, A_1 and A_2 (or B_1 and B_2) must be connected to ground.

3. When A_1 and A_2 (or B_1 and B_2) are used as inputs, A^* (or B^*) must be open, or used to perform wired-OR logic.

Total Power Dissipation = 105 mW typ/pkg



ELECTRICAL CHARACTERISTICS

Output voltage (logic level) tests are shown only for each output. The complete circuit can be tested by following the truth table.

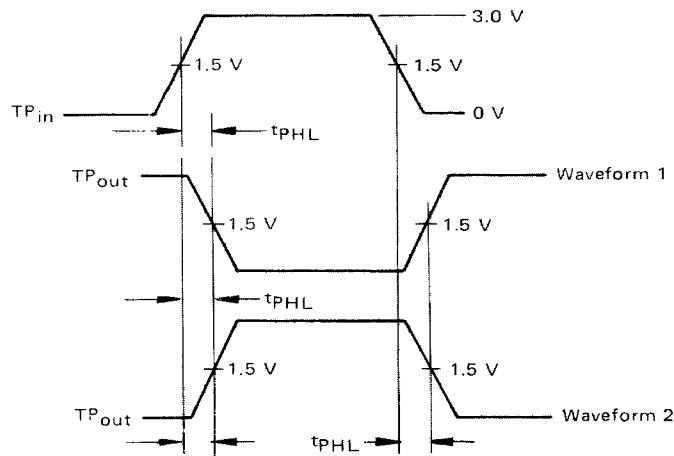
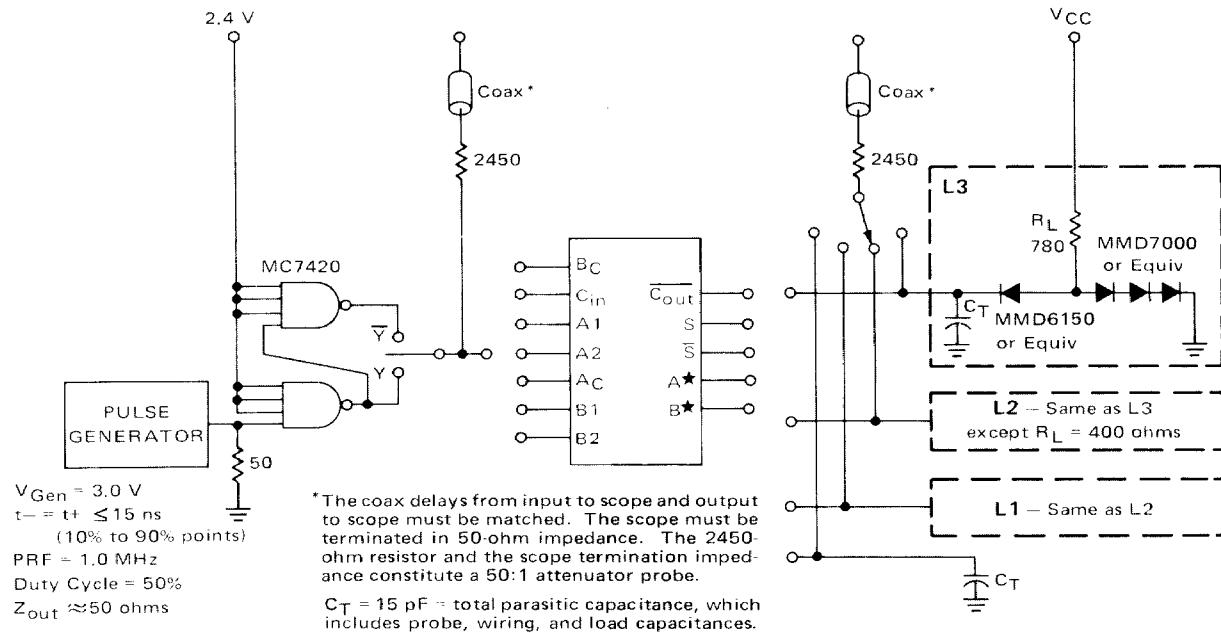
$$V = V_{CC} = \text{Pin } 14 [4] \\ \text{Gnd} = \text{Pin } 7 [11]$$

TEST CURRENT/VOLTAGE VALUES (All Temperatures)

Characteristic	Symbol	Pin Under Test	Test Limits	TEST CURRENT/VOLTAGE APPLIED TO PINS LISTED BELOW:								Gnd								
				Min	Max	Unit	I _{L1}	I _{OL2}	I _{OL3}	I _{OH1}	I _{OH2}	V _L	V _{IH}	V _{IHH}	V _R	V _{ILT}	V _{IHT}	V _{CCL}	V _{CCH}	
Input Forward Current	I _{IL}	B*	-2.6	mAdc	-2.6	mAdc	-	-	-	-	-	-	8*	-	-	-	-	-	V	B1,B2
	BC	-1.6	-	-	-1.6	-	-	-	-	-	-	-	BC	-	-	-	-	-	V	B1,B2
	C _{in}	-8.0	-	-	-8.0	-	-	-	-	-	-	-	C _{in}	-	-	-	-	-	V	B1,A,C
	A1	-1.6	-	-	-1.6	-	-	-	-	-	-	-	A1	-	-	-	-	-	V	A1,A2
	A2	-1.6	-	-	-1.6	-	-	-	-	-	-	-	A2	-	-	-	-	-	V	A1,A2
	A*	-2.6	-	-	-1.6	-	-	-	-	-	-	-	A*	-	-	-	-	-	V	A1,A2
	AC	-1.6	-	-	-1.6	-	-	-	-	-	-	-	AC	-	-	-	-	-	V	A1,A2
Leakage Current	I _{IH}	B1	-	μAdc	-	15	μAdc	-	-	-	-	-	B1	-	-	-	-	-	V	B1,B2,A1,A2,A*
	BC	-	200	-	200	μAdc	-	-	-	-	-	-	C _{in}	-	-	-	-	-	V	A1,A2,B1,B2
	C _{in}	-	15	-	15	μAdc	-	-	-	-	-	-	A1	-	-	-	-	-	V	A1
	A1	-	-	-	-	-	-	-	-	-	-	-	A2	-	-	-	-	-	V	A1
	A2	-	-	-	-	-	-	-	-	-	-	-	AC	-	-	-	-	-	V	B2
	AC	-	-	-	-	-	-	-	-	-	-	-	B1	-	-	-	-	-	V	B1
	B1	-	-	-	-	-	-	-	-	-	-	-	B2	-	-	-	-	-	V	B1
	B2	-	-	-	-	-	-	-	-	-	-	-	B1	-	-	-	-	-	V	B1
Leakage Current	I _{IHH}	B1	-	1.0	mAdc	-	1.0	mAdc	-	-	-	-	B1	-	-	-	-	-	V	B1,A,C
	BC	-	-	-	-	-	-	-	-	-	-	-	C _{in}	-	-	-	-	-	V	A1,A2,B1,B2
	A1	-	-	-	-	-	-	-	-	-	-	-	A1	-	-	-	-	-	V	A1
	A2	-	-	-	-	-	-	-	-	-	-	-	A2	-	-	-	-	-	V	A1
	AC	-	-	-	-	-	-	-	-	-	-	-	AC	-	-	-	-	-	V	A1
	B1	-	-	-	-	-	-	-	-	-	-	-	B1	-	-	-	-	-	V	B2
	B2	-	-	-	-	-	-	-	-	-	-	-	B2	-	-	-	-	-	V	B2
Output Output Voltage	V _{OL}	B*	-0.4	Vdc	-0.4	Vdc	B*	-	-	-	-	-	B1	-	-	-	-	-	V	B1,B2
	C _{out}	-	-	-	-	-	-	-	-	-	-	-	C _{in}	-	-	-	-	-	V	A1,B1
	S	-	-	-	-	-	-	-	-	-	-	-	B1	-	-	-	-	-	V	B1
	̄S	-	-	-	-	-	-	-	-	-	-	-	B2	-	-	-	-	-	V	B1,B2
	A*	-	-	-	-	-	-	-	-	-	-	-	A1	-	-	-	-	-	V	A1,A2
Short-Circuit Current	I _{OST}	V _{OH}	2.4	-	Vdc	2.4	-	Vdc	-	-	B*	-	C _{out}	-	-	-	-	-	V	C _{out} ,A1,A2,A,C,B1
	S	-	-	-	-	-	-	-	-	-	-	-	S	-	-	-	-	-	V	C _{in} ,A1,A2,B1,B2,C _{in} ,A1,A,C,B1
	̄S	-	-	-	-	-	-	-	-	-	-	-	A*	-	-	-	-	-	V	C _{in} ,A1,A,C,B1
	B*	-	-	-	-	-	-	-	-	-	-	-	S	-	-	-	-	-	V	C _{in} ,A1,A,C,B1
	C _{out}	-20	-70	mAdc	-18	-70	mAdc	-	-	-	-	-	B1	-	-	-	-	-	V	C _{out} ,A1,A2,A,C,B1
	S	-	-57	-	-57	-	-	-	-	-	-	-	B2	-	-	-	-	-	V	C _{in} ,S,A1,A,C,B1
	̄S	-	-57	-	-57	-	-	-	-	-	-	-	B1	-	-	-	-	-	V	C _{in} ,B1,S,A1,A2,B1,B2
Power Requirements	Power Supply Drain	I _{CC}	V	-	31	mAdc	-	35	mAdc	-	-	-	-	-	-	-	-	-	V	-

*Only one output should be shorted at a time.

SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



TEST PROCEDURES (T_A = 25°C)

TEST	PIN UNDER TEST	INPUT							OUTPUT						MAX LIMIT	WAVE-FORM
		BC	C _{in}	A1	A2	A _C	B1	B2	C _{out}	S	S	A★	B★			
IPLH C _{out}	4 [8]	Y					Gnd		L3					17 ns	1	
IPLH C _{out}		Y	2.4 V				Gnd		L3					12 ns	1	
IPLH C _{out}		Y	2.4 V	Gnd			Gnd		L3					25 ns	2	
IPLH C _{out}		Y	2.4 V	Gnd			Gnd		L3					55 ns	2	
IPLH S	5 [9]		2.4 V	Gnd			Y	Gnd	L3	L1	L2			70 ns	2	
IPLH S	5 [9]		2.4 V	Gnd			Y	Gnd	L3	L1	L2			80 ns	2	
IPLH S	6 [10]	Y	2.4 V				Gnd		L2					55 ns	2	
IPLH S	6 [10]	Y	2.4 V				Gnd		L2					75 ns	2	
IPLH A★	10 [14]			Y	2.4 V							C _T		65 ns	1	
IPLH A★	10 [14]			Y	2.4 V							C _T		25 ns	1	
IPLH B★	1 [5]					Y	2.4 V					C _T		65 ns	1	
IPLH B★	1 [5]					Y	2.4 V					C _T		25 ns	1	